

IN THE CLAIMS:

Applicants propose to amend claims 7 through 13, 16, 19, 22, 25 through 27 and 29 through 31 herein. Applicants note that the amended claims are presented in accordance with 37 CFR 1.73(b)(2) and (d). Please enter these claims as amended.

5. (previously presented) A testing apparatus for controlling positioning of a circuit before, during and after a circuit test is performed on the circuit, the circuit test determining a first and a second test condition of the circuit, the apparatus comprising:

- a) a positioning apparatus having a first port and a second port and [capable of displacement to] a first position and a second position, said first port receiving the circuit for testing;
- b) a testing apparatus for securing said circuit during a testing of the circuit, said positioning apparatus displaced to said second position during testing;
- c) a testing control pin for retaining said circuit in said first port prior to the testing and for allowing a transfer of said circuit from said first port to said second port subsequent to the testing;
- d) a first track for receiving said circuit from said second port when said circuit test finds said circuit to have the first test condition, said positioning apparatus being in said first position; and
- e) a second track for receiving said circuit from said second port when said circuit test finds said circuit to have the second test condition, said positioning apparatus being in said second position.

7. (currently amended) An integrated circuit testing apparatus for testing an integrated circuit leaving an integrated circuit singulation station, comprising: a receiving apparatus positioned to receive untested integrated circuits from the integrated circuit singulation station;

a testing apparatus positioned to receive the untested integrated circuits from the receiving apparatus and test the integrated circuits to identify defective integrated circuits and non-defective integrated circuits, the testing apparatus including a holding station moveable with the testing apparatus, a first position, and a second position, the testing apparatus while in the first position allowing tested integrated circuits to proceed to the holding station and allowing untested integrated circuits to be received from the receiving apparatus; and

a separating apparatus connected to the testing apparatus to separate defective integrated circuits from non-defective integrated circuits after testing thereof, the separating apparatus including a first track for receiving integrated circuits from the holding station in the first position, and a second track for receiving integrated circuits from the holding station in the second position.

8. (currently amended) The apparatus of claim 7, wherein the testing apparatus while in the second position will electrically test the integrated circuit.

9. (currently amended) The apparatus of claim 8, further comprising:
the holding station while in the first position holding defective integrated circuits from proceeding to the separating apparatus, and allowing non-defective integrated circuits to proceed to the first track of the separating apparatus; and
the holding station while in the second position releasing defective integrated circuits to the second track of the separating apparatus.

10. (currently amended) An integrated circuit testing apparatus for testing an integrated circuit leaving an integrated circuit singulation station, comprising:
a loading apparatus for supplying the integrated circuit leaving the integrated circuit singulation station to the integrated circuit testing apparatus;

a receiving apparatus positioned to receive untested integrated circuits from the integrated circuit singulation station;

a testing apparatus positioned to receive the untested integrated circuits from the receiving apparatus and test the integrated circuits to identify defective integrated circuits and non-defective integrated circuits, the testing apparatus including a holding station, a first position, and a second position, the testing apparatus while in the first position allowing tested integrated circuits to proceed to the holding station and allowing untested integrated circuits to be received from the receiving apparatus; and

a separating apparatus connected to the testing apparatus to separate defective integrated circuits from non-defective integrated circuits after testing thereof, the separating apparatus including a first track for receiving non-defective integrated circuits from the holding station in the first position and a second track for receiving defective integrated circuits from the holding station in the second position.

11. (currently amended) The apparatus of claim 10, wherein the testing apparatus while in the second position will electrically test the integrated circuit.

12. (currently amended) The apparatus of claim 11, further comprising: the holding station while in the first position holding defective integrated circuits from proceeding to the separating apparatus, and allowing non-defective integrated circuits to proceed to the first track of the separating apparatus; and the holding station while in the second position releasing defective integrated circuits to the second track of the separating apparatus.

13. (currently amended) A method of testing an integrated circuit in a testing apparatus having a test site, a holding station, a non-defective integrated circuit track, a defective integrated circuit track, a first position, and a second position, after the singulation of the integrated circuit in an integrated circuit singulation apparatus, the method comprising:

transferring the integrated circuit from the integrated circuit singulation apparatus;
receiving the integrated circuit at the testing apparatus while the testing apparatus is in the first
position;
moving the testing apparatus to the second position;
testing the integrated circuit to identify defective and non-defective conditions of the integrated
circuit;
moving the testing apparatus to the first position to allow the tested integrated circuit to proceed
to the holding station in a first unloading position while receiving a second singulated
integrated circuit into the testing apparatus;
allowing non-defective integrated circuits to proceed to the non-defective integrated circuit track
from the first unloading position; and
moving the holding station to a second unloading position and allowing defective integrated
circuits to proceed to the defective integrated circuit track.

16. (currently amended) A method of testing an integrated circuit after the singulation
thereof using a testing apparatus having a test site, a holding station, a non-defective integrated
circuit track, a defective integrated circuit track, a first position, and a second position, the
method comprising:
transferring the integrated circuit from the integrated circuit singulation apparatus;
receiving the integrated circuit at the testing apparatus while the testing apparatus is in the first
position;
moving the testing apparatus to the second position;
testing the integrated circuit thereby identifying defective and non-defective conditions thereof;
moving the testing apparatus to the first position after testing of the integrated circuit;
allowing the tested integrated circuit to proceed to the holding station in a first unloading
position;
receiving a second singulated integrated circuit into the testing apparatus while in the first
position;

unloading non-defective integrated circuits to the non-defective integrated circuit track from the first unloading position; and
moving the holding station to a second unloading position and unloading defective integrated circuits to the defective integrated circuit track.

19. (currently amended) A method of testing an integrated circuit in a testing apparatus having a test site, a holding station, a non-defective integrated circuit track, a defective integrated circuit track, a first position, and a second position, after the singulation of the integrated circuit in an integrated circuit singulation apparatus, the method comprising:
receiving the integrated circuit at the testing apparatus while the testing apparatus is in the first position;
moving the testing apparatus to the second position;
testing the integrated circuit to identify defective and non-defective conditions of the integrated circuit;
moving the testing apparatus to the first position to allow the tested integrated circuit to proceed to the holding station in a first unloading position while receiving a second singulated integrated circuit into the testing apparatus;
allowing non-defective integrated circuits to proceed to the non-defective integrated circuit track from the first unloading position; and
moving the holding station to a second unloading position and allowing defective integrated circuits to proceed to the defective integrated circuit track.

22. (previously presented) A method of testing an integrated circuit after the singulation thereof using a testing apparatus having a test site, a holding station, a non-defective integrated circuit track, a defective integrated circuit track, a first position, and a second position, the method comprising:
receiving the integrated circuit at the testing apparatus while the testing apparatus is in the first position;

moving the testing apparatus to the second position;
testing the integrated circuit thereby identifying defective and non-defective conditions thereof;
moving the testing apparatus to the first position after testing of the integrated circuit;
allowing the tested integrated circuit to proceed to the holding station in a first unloading
position;
receiving a second singulated integrated circuit into the testing apparatus while in the first
position;
unloading non-defective integrated circuits to the non-defective integrated circuit track from the
first unloading position; and
moving the holding station to a second unloading position and unloading defective integrated
circuits to the defective integrated circuit track.

25. (currently amended) An apparatus for testing singulated integrated circuits,
comprising:
a testing apparatus movable between a first position and a second position receiving untested
integrated circuits while in the first position and identifying first and second test
conditions of an integrated circuit while in the second position;
a holding station coupled to the testing apparatus and movable between the first position and the
second position, the holding station receiving tested integrated circuits from the testing
apparatus while in the first position and releasing tested integrated circuits having the first
test condition while at the first position and releasing tested integrated circuits having the
second test condition while at the second position;
a first track for receiving tested integrated circuits having the first test condition from the holding
station when the holding station is at the first position; and
a second track for receiving tested integrated circuits having the second test condition from the
holding station when the holding station is at the second position.

26. (currently amended) The apparatus of claim 25, wherein the testing apparatus and the holding station include at least one integral member moveable between the first position and the second position.

27. (currently amended) A method of testing singulated integrated circuits in a testing apparatus having a first position, a second position, a first integrated circuit track, a second integrated circuit track, and a holding station, comprising:
receiving an untested, singulated integrated circuit into the testing apparatus while in the first position;
moving the untested, singulated integrated circuit to the second position;
testing the untested, singulated integrated circuit to determine first and second test conditions thereof;
moving the tested, singulated integrated circuit back to the first position;
allowing the tested, singulated integrated circuit to move to the holding station in the first position;
receiving another untested, singulated integrated circuit into the testing apparatus while in the first position;
releasing tested, singulated integrated circuits having the first test condition to the first integrated circuit track while the holding station is in the first position; and
releasing tested, singulated integrated circuits having the second test condition to the second integrated circuit track while the holding station is in the second position.

29. (currently amended) An apparatus for testing singulated integrated circuits, comprising:
a loading apparatus for supplying an integrated circuit leaving an integrated circuit singulation station to the apparatus;

a testing apparatus movable between a first position and a second position for receiving untested integrated circuits while in the first position and identifying first and second test conditions of an integrated circuit while in the second position;
a holding station coupled to the testing apparatus and movable between the first position and the second position, the holding station receiving tested integrated circuits from the testing apparatus while in the first position and releasing tested integrated circuits having the first test condition while at the first position and releasing tested integrated circuits having the second test condition while at the second position;
a first track for receiving tested integrated circuits having the first test condition from the holding station when the holding station is at the first position; and
a second track for receiving tested integrated circuits having the second test condition from the holding station when the holding station is at the second position.

30. (currently amended) The apparatus of claim 29, wherein the testing apparatus and the holding station include at least one integral member moveable between the first position and the second position.

31. (currently amended) A method of testing singulated integrated circuits in a testing apparatus having a first position, a second position, a first integrated circuit track, a second integrated circuit track, and a holding station, comprising:
transferring the integrated circuit from the integrated circuit singulation apparatus;
receiving an untested, singulated integrated circuit into the testing apparatus while in the first position;
moving the untested, singulated integrated circuit to the second position;
testing the untested, singulated integrated circuit to determine first and second test conditions thereof;
moving the tested, singulated integrated circuit back to the first position;

allowing the tested, singulated integrated circuit to move to the holding station in the first position;

receiving another untested, singulated integrated circuit into the testing apparatus while in the first position;

releasing tested, singulated integrated circuits having the first test condition to the first integrated circuit track while the holding station is in the first position; and

releasing tested, singulated integrated circuits having the second test condition to the second integrated circuit track while the holding station is in the second position.